

### Enabling of high Q Micromachined Planar Filter Components Part I

ESA GSTP- 4 Program:

ESTEC Contract No. 19621 / 06 / NL /PA

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www.reinhardt-microtech.ch



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technology

thin film



- introduction + basics



## Introduction (I / VI)

#### **Basic Project's requests:**

- Transform an academic design / process flow into an industrial whole wafer process
- including packaging of the devices wafer level
  - show first environmental tests



## Introduction (II / VII)

basics I

The incoupled EM – wave passes the  $\lambda$  / 2 designed electrode structure and comes to resonate at the selected frequencies.



# To increase the Q – figure the wave is enclosed at an Au coated cavity.



### Introduction (III / VII)

basics II



**Q** – figures up to 600 can be realised

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## Introduction (IV/ VII)

Strucuring for both sides	
Opening of SiO2 for Si etch	
BCB - Coating	
BCB - Metallisation	
Structuring of BCB - Metallisation	
Si deep etching	

 Transform an academic design / process flow into an industrial whole wafer process



## **Introduction (V / VII)**

including packaging of the devices





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## Introduction (VI / VII)

#### show first environmental tests



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### **Introduction (VII / VII)**

#### show first environmental tests





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#### of part I

#### introduction and basics



### Enabling of high Q Micromachined Planar Filter Components Part II

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### **Content** (part II of final presentation)

- specification
- theory and design
- device overview
- processes on wafer level
- development of packaging design
- processes for packaging
- realised filters measurements
- outlook

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### **Specifications**

**Technical specification:** 

down - converter filter at K<sub>a</sub> - band

f<sub>0</sub> = 19.825 GHz

Initial bandwidth ~ 0.75 GHz

min. loss at  $f_0 \sim -3$  dB etc.

given: electrode and device layout





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## **Theory and Design (I)**

#### Theory:

was covered throughout the project by Xlim:

- basic layout (pre given, not altered)
- failure budgets (tolerances)
- design checks
- practical proof of new packaging design



## **Theory and Design (II)**

### **Design:**

#### changed to practical waver level stacking





### **Theory and Design (III)**

### **Design:**

changed to practical waver level stacking





### **Device overview I**

# The devices are built up out of 3 stacked wafers X –ray picture:



- 1. microstrip Line (waveguiding part)
- 2. RF input output
- 3. BCB membrane
- 4. conducting adhesive



### **Device overview II**

## The devices are built up out of 3 stacked wafers forming a resonating cavity:



- 1. microstrip Line (waveguiding part)
- 2. ground metallisation top wafer
- 3. BCB membrane
- 4. cavity divided by BCB membrane
- 5. ground metallisation bottom wafer
- 6. area for electromagnetic shielding
- 7. high ohmic Si



## Incoming inspection Cleaning Metallisation both sides Lithography both sides Si - etch

Wafer Processes I

Process follow up for Bottom wafer (I):

- cleaning
- metallisation (both sides)
- lithography (both sides)
- Si etch



### Wafer Processes II





Wafer level control steps

go to under fill process



Process follow up for

Bottom wafer (II):

- 2nd metallisation

- electroplating (top 8.5;

slope 7, bottom 6.7 µm Au)







### Wafer Processes III



Middle wafer key processes:

- BCB Processing
- Si etch simultaneously
- handling of thinned wafers



### Wafer Processes IV



#### **Top wafer:**

#### prepared for underfill



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### Development of the Packaging Design I



initial design:

manual gluing of

3 parts

- complicated single alignment
- cumbersome handling



### Development of the Packaging Design I



new design considerations:

- partially etched openings
- a single wafer alignment system

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## **Processes Packaging I**

#### **Complete Underfill Process:**



by selecting proper process parameters a well defined flow of underfill can be achieved





complete / non - complete fill of device edges



### realised filter

- device picture





## realised filter (I / IV)

#### - RF – Measurements I (overview)



#### **2** golden samples





## realised filter (II / IV)

#### - RF – Measurements II (detail)



#### 2 golden samples; enlargement

compare theory and practical measurements

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## realised filter (III / IV)

#### - RF – Measurements temperature dependant





## realised filter (IV / IV)

#### - RF – Measurements temperature dependant



E 0604 enlargement S<sub>11</sub> + S<sub>21</sub>, 3 temperatures

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**Outlook I** 

The success story of this project was guided by:

- good theoretical investigations
- step by step development of packaging
- mutual help of all project partners



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### **Outlook II**

# The success story of this project was guided by (non technical view)

- a personal frictionless working together
- a successful teamwork
- resulting in sound friendship



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